S. Mogck, B. J. Kooi, and J. Th. M. De Hosson*

M. W. Finnis

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I. INTRODUCTION

Metal ceramic interfaces play an important role in the performance of many advanced materials¹⁻³ Examination of electron microscopy (HRTEM) may lead to a more fundamental insight into the adhesion and the nature of bonding between dissimilar materials.¹ In fact, the heterophase interface structure is a fingerprint of possible bonding across the interface. Interface dislocations serve as detectors of the coupling between these dissimilar materials and HRTEM serves as a sensor.¹ Nevertheless, to determine the atomic structure of interfaces it is essential that experimental HRTEM observations are compared with image simulations. Quantitative structure retrieval from HRTEM micrographs has demonstrated the need of incorporating atomic bonding, i.e., a more accurate description of the electron scattering in thin crystals.^{4,5} At present HRTEM image simulations rely on scattering factors of neutral atoms and standard calculation of dynamic electron diffraction starts with a superposition of the scattering potential of atoms. The atomic form factors are presented in the literature,⁶ but only at specific sampling points. To interpolate the atomic form factors for any spatial frequency the data are fitted using a sum of Gaussian functions as introduced by Doyle and Turner.⁶ However, the difference between neutral and ionic scattering is very significant.⁷ On the other hand, detailed experimental investigations on structure factors obtained with the convergent beam electron diffraction technique⁸ revealed that the effect of ionicity on images is rather small. Furthermore, the effect of ionicity on HRTEM image simulations based on firstprinciples calculations was studied in sapphire by Gemming images of neutral atoms. On the other hand, Fresnel-like features are expected to be present at places where the mean inner potential changes rapidly^{10,11} and this observation is relevant for metal-oxide interfaces.

For a comparison with experimental observations reference is made to Refs. 1 and 12–14. Metal-oxide interfaces were fabricated by internal oxidation to obtain many small oxide precipitates inside a metal matrix. This method produces many clean interfaces for investigations in each sample and such internally oxidized samples are easy to prepare for transmission electron microscopy. MgO precipitates in Ag after internal oxidation show no clear facets and are nearly spherical with a size of 5 nm.¹² A more complex system, for which no first-principles calculations have yet been made, is obtained by internal oxidation of Ag-3 at. % Mn at 900 °C for 1 h. The product in this case comprises Mn₃O₄ (tetragonal distorted spinel, I4/amd) precipitates bound by {111} planes with a size of $5-20 \text{ nm.}^{13}$ Figure 1 shows an example of a HRTEM image of in the (110) viewing direction of a polar {111} Ag-Mn₃O₄ interface. At the interface a distinct bright line, as indicated by the arrow, is present that can be a consequence of the bonding, image charge formation in the metal as a reaction to the polar interface and/or charge transfer. In order to test if these effects significantly influence HRTEM images, image simulations of the Ag-MgO interface based on the charge-density distribution



FIG. 1. Experimental HRTEM micrograph of an {111} Ag $-Mn_3O_4$ interface in the $\langle 110 \rangle$ viewing direction. The bright line at the outermost monolayer at the metal side of the interface is indicated by a white arrow.

derived form first-principles calculations are performed. The bonding across the interface is analyzed by comparing the "realistic" interface calculations with those involving atomic blocks with free surfaces and with those of neutral atoms. In this way, our study addresses the question if the "realistic" image simulations of HRTEM images lead to deviations (at the interface only or at both the interface and within the bulk) from the simulation involving only neutral atoms.

II. CHARGE-DENSITY CALCULATIONS

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FIG. 2. Schematic illustration of the {111} Ag-MgO model with vacuum on both sides of the interface. This model is used to obtain the relaxed Ag coordinates for a model without the presence of a vacuum (see Fig. 3).

The {111} Ag-MgO interface is known to be semicoherent with a mismatch of 3.07%. The ratio of the MgO and Ag lattice constants is approximately 34/33 and with this ratio, the smallest possible periodic structure representing the interface would contain at least 999 Mg or O atoms and 1156 Ag atoms, which is currently far too big for first-principles calculations. Nevertheless, this small mismatch implies that a substantial fraction of the interface is coherent. Calculations on the {111} coherent Ag-MgO interface therefore provide realistic information about the coherent patches of the real interface. The small mismatch of the Ag-MgO interface was eliminated by adapting the lattice parameters of both Ag and MgO to 4.20 Å. The relaxation of the Ag atoms with respect to the MgO was carried out in slab geometry with free surfaces on both sides of the interface and periodic boundary conditions. The Brillouin zone of the Ag-MgO was sampled (4|3,2) (Ag|O,Mg) layers for the oxygen-terminated interface were relaxed to < 0.02 eV/Åusing the Broyden-Fletcher-Goldfarb-Shanno²¹⁻²⁴ procedure.

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as "polar" surfaces. For more details see Ref. 25. During the \times 5.144 Å \times 2.97 Å and 24.97 Å \times 5.144 Å \times 2.97 Å for the oxygen and Mg-terminated interfaces were kept fixed. Comparison of calculated polar {222} MgO-Cu interfaces with a slab geometry of (3,3|3) (Mg,O|Cu) layers in the ABCabc stacking sequence and (5,5|5) (Mg,O|Cu) yielded similar spect to MgO were used as an input for the relaxation of a larger polar Ag-MgO model, keeping the coordinates of Mg and O unchanged. Figure 3 shows the periodic slab geometry of (7|4,3) (Ag|O,Mg) layers in the CABCABCabcabca stacking sequence without the presence of a vacuum.

In principle, the calculation holds for a multilayer. To extract the charge transfer across the interface and the electron redistribution due to metal-oxide bonding the charge-density difference must be calculated. This was performed with Ag-MgO interface was calculated. Afterwards the individual slab calculation of MgO and Ag was carried out in the same supercell by just removing for each case the block of Ag atoms or of MgO, respectively. In all calculations, the number of k points and cutoff energy were kept constant. The calculated charge density of the Ag-MgO interface was subtracted from sum of the charge densities of the Ag and MgO slabs to obtain the charge density difference $\Delta \rho(\vec{r})$, which լ represents the charge representation of the c

III. AB INITIO HRTEM IMAGE SIMULATION

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$$V(\vec{k}) = \frac{2me}{4\pi^2 \varepsilon_0 h^2} \Biggl\{ \sum_{n,j} \Biggl[\frac{\rho_{n,j} e^{2\pi i \vec{k} \cdot \vec{r}} d\vec{r}}{k^2} \Biggr] - \sum_{nx,ny,nz} \Biggl[\frac{\int \Delta \rho(nx,ny,nz) e^{2\pi i \vec{k} \cdot \vec{r}} d\vec{r}}{k^2} \Biggr] \Biggr\}, \qquad (1)$$

We shall refer to image simulations based on firstprinciples calculations of the charge density as *ab initio* simulations. These can now be compared with the image contrast provided by a standard HRTEM simulation program, e.g., EMS with Doyle and Turner neutral atom scattering factors. In all cases, the EMS program²⁷ was used to simulate



4. Charge-density difference $\Delta \rho(\vec{r}) = \rho_{\text{Ag-MgO}}(\vec{r})$ FIG $-[\rho_{Ag \ slab}(\vec{r}) + \rho_{MgO \ slab}(\vec{r})]$ of the Ag-MgO interface (CASTEP) referred to self-consistent free surfaces. The cross section of the contour plot goes through (0.5,0,0) to get a cross section of a Ag-O bond at the interface. The range $\pm 0.1 \ e/\text{\AA}^3$ is chosen for a better visualization. The actual $\Delta \rho$ values range from -1.026 to 0.453 $e/Å^3$.

The ab initio HRTEM simulations of bulk MgO and sapphire included the ionic character of the bonding into the projected potentials $V(\vec{k})$ by augmenting the atomic charge densities with the self-consistent charge-density differences. be observed at the thickness (defocus) value of 71 Å (-750 Å) between the conventional simulation and the image simulation corrected with the charge-density map. The in MgO could be described as a superposition of spherical Mg^{2+} and O^{2-} ions,²⁸ although we note that the numerical values of ionic charge are not uniquely defined, and indeed the O²⁻ ion is unstable in vacuum. This high degree of ionicity is presumably responsible for the reversal in contrast in the HRTEM image simulation. By comparison, the incorporation of the ionic environment in sapphire does not signifi-ॅ<table-cell><list-item><list-item>foodmann(foodmann)(foodmannn)(foodmannn)(foodmannn)(foodmannn)(foodmannn)(foodmannn)(foodmannn)(foodmann)(foodmannn)(foodmann)(foodmannn)(foodma result we reproduced.



A. {111} Ag-MgO interface (O-terminated)

In the following, three different approaches to the image simulation for {111} Ag-MgO interfaces will be evaluated:

(a) Standard HRTEM simulation using the Doyle-Turner scattering factor.

(c) Standard HRTEM simulation adding a correction term for case (b) and the ionicity in MgO (DACAPO), i.e., the charge redistribution is referred to neutral atoms.

Contour plots of the charge-density difference [through (0.5,0,0) to get a cross section of a Ag—O bond] reveal a similar behavior of the charge redistribution at the interface, but as expected not for the bulk phases (see Figs. 4 and 5). Figure 5 shows discontinuities near the core but actually this discontinuity is not real. A plot range of $\pm 0.1 \ e/Å^3$ is chosen for better visualization of the charge density at the interface. The higher electron densities $>0.1 \ e/Å^3$ are not depicted in the contour plots, but were included in the HRTEM correction terms. Furthermore, since we are working with slabs, one would not expect perfect fcc symmetry in the difference charge density at Ag but that we do not see much evidence of any violation of fcc symmetries to graphical accuracy at the central Ag atoms in the cross section shown.





FIG. 7. HRTEM image simulation of Ag-MgO in the $\langle 110 \rangle$ viewing direction using a defocus value of -750Å and thicknesses of 45, 59, 74, and 84 Å.

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A set of HRTEM simulated images of the {111} Ag—MgO interface is shown in Figs. 6 and 7. The arrows in Figs. 6 and 7 indicate the interface between the terminating oxygen and silver layer. Figure 6 shows HRTEM simulations



FIG. 8. Line profiles of simulated images across $\{111\}$ Ag-MgO interface (O-terminated) using a defocus value of -750 Å and a thickness of 74 Å. These line profiles correspond to the simulated images in the third through fourth of Fig. 7.

for three different defocus values of -480, -600, and -720 Å for cases (a), (b), and (c) with a constant thickness of 74 Å. Figure 6(a) refers to the standard simulation with the Doyle-scattering factors are used to describe neutral and spherical atoms. In Fig. 6(b) the standard simulation corrected with the the individual slabs of Ag and MgO (by just removing in the first calculation MgO and second case Ag) was performed with a constant supercell dimension and cuttoff energy. This means that the corrected HRTEM image in Fig. 6(b) includes no bonding environment and ionic character of the bulk, but the charge transfer and charge redistribution directly at the interface. In Fig. 6(c) the standard simulation is corrected with the charge density obtained with DACAPO (see Sec. II). in Fig. 6(b) and additionally the bonding environment in the bulk. This was performed by subtracting the fully self-charge of the individual atoms in the ground state. The simulated HRTEM in Fig. 6(c) is corrected with the charge density including the bonding environment and the charge redistribution at the interface. The terminating oxygen monolayer changes contrast among the three different cases; note espe-standard HRTEM simulation [case Fig. 6(a)] and the corrected HRTEM simulation [see case Fig. 6(c)] for a given defocus value. Including the bonding of individual atoms in the correction term [case (c)] the brightness is increased at the terminating oxygen monolayer compared with the brightness of the oxygen layers in the bulk (see Fig. 7, right column). For all defocus-thickness variations a contrast change in the corrected HRTEM simulations in the outmost Ag layer at the Ag-MgO interface is barely detectable. The electrons and inhibit a contrast change at the metal side of the interface.

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line profiles correspond to the simulated images in the third row of Fig. 7. The line profile of the corrected image simulation of case (c) shows that the contrast minima and maxima are inverted compared with simulation of neutral MgO [case (a) and (b)], whereas in the bulk of Ag similar contrast behavior is observed in all cases (see Fig. 8). Furthermore, the terminating oxygen layer (when compared to the other



FIG. 9. Charge-density difference $\Delta\rho(\vec{r}) = \rho_{Ag-MgO}(\vec{r}) - [\rho_{Ag \ slab}(\vec{r}) + \rho_{MgO \ slab}(\vec{r})]$ of the Ag-MgO interface. The cross section of the contour plot goes through (0.5,0,0) to get a cross section of an Ag-Mg bond at the interface. The range $\pm 0.1 \ e/Å^3$ is chosen for a better visualization. The actual $\Delta\rho$ values range from -0.1473 to $0.0425 \ e/Å^3$.



FIG. 10. HRTEM image simulation of a Mg-terminated Ag -MgO interface in the $\langle 110 \rangle$ viewing direction using defocus values -120 Å and -750 Å with a thickness of 74 Å. The panels (a), (b), and (c) correspond to the defined correction terms, as described in Sec. IV.

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B. {111} Ag-MgO interface (Mg-terminated)

The same procedure was applied to the Mg-terminated {111} Ag-MgO interface. A contour plot of the charge density difference through (0.5,0,0) to get a cross section of an Ag-Mg bond for case (b) (including only the charge redistribution at the interface) is displayed in Fig. 9. Figure 9 indicates that the charge redistribution in the terminating Ag layer is less pronounced at the Mg-terminated layer than in the case of an oxygen-terminated interface (Fig. 4). A set of HRTEM simulated images is shown in Fig. 10 of an Mg-terminated {111} Ag-MgO interface. The arrows in Fig. 10 indicate the interface between the terminating magnesium and silver layer.

The line profile of the corrected image simulation of case (c) shows that the contrast minima and maxima are inverted compared with a simulation excluding the bonding environment of the bulk MgO [case (a) and (b)], whereas in the bulk of Ag similar contrast behavior is observed in all cases, as shown in Fig. 11. At the terminating Ag and Mg layers, the contrast does not change significantly (compare within Figs. 10 and 11). This is in agreement with the small charge redistribution present at the Mg-terminated {111} Ag—MgO interface compared with the corresponding O-terminated interface (compare Fig. 4 versus Fig. 9).

V. DISCUSSION AND CONCLUSIONS

In the DFT plane-wave calculations, we have used the LDA approximation (CASTEP code) as well as the GGA approximation (DACAPO code), in accordance with the generated ultrasoft pseudopotentials used in both codes. Indeed we have not analyzed the GGA versus LDA treatments of exchange and correlation to see which gives better results. To do so would require a theory that is superior to both of them, or sufficiently accurate experimental data. Unfortunately neither is currently available to us. We must be content at this point to say that the two approaches give qualitatively similar results. As stated before, for reasons of consistency we used the same exchange-correlation functional for the applications as was used to generate the component pseudopotentials. Nevertheless, the point is that we need to work with two different pseudopotentials, one generated with LDA, the other with GGA, and this was achieved by using the two different codes. This is purely a matter of convenience, and no scientific issues seem to be at stake: both are plane-wave pseudopotential codes, so given the same pseudopotentials and the same exchange-correlation functional, they should give identical results. Perhaps in an ideal world we would have used the same basic code with modular implementations of both GGA and LDA.

Furthermore it should be stressed that in previous experimental work¹ we concentrated on the dislocation network along semicoherent interfaces. Our reason for not considering the triangular network of dislocations, or any other network of dislocations, is simply that we want to make image simulations explicitly of the coherent patches between misfit dislocations, for comparison of the electron density models with each other and with experimental data taken from such coherent patches. It would be difficult to make image simu-



FIG. 11. Line profiles of simulated images across $\{111\}$ Ag-MgO interface (Mg terminated) using defocus value of -750 Å and a thickness of 74 Å. These line profiles correspond to the simulated images in the right column of Fig. 10.

The MIGS diminish the ionic character of metal-oxide bonding, resulting in less charge transfer and electrostatic potential shift at the interface. From the observed change in simulations it can be concluded that not only the ionicity and nonspherical atomic form factors in the slabs of pure oxide, but also the charge transfer between oxide and metal is important. Some effort is necessary to calculate ab initio charge-density difference maps, but this is recovered by an increase in the reliability of quantitative image matching. In particular, the reliance on conventional HRTEM image simulations of oxides can lead to a misinterpretation of the experimental image. For instance, the estimated thickness obtained with image matching of the experimental image reveals that the calculated image is thinner using screened potentials (incorporating the ionicity in HRTEM image simulations) than when using the neutral atom potential.³⁰ Any HRTEM image simulation starts with the determination of atomic scattering factors to calculate the projected potential. It should be pointed out that the scattering factors from Doyle and Turner,⁵ parametrized as the sum of four Gaussians, are only valid up to 2.0 nm⁻¹. This leads to an under-we assume that the atomic scattering factors themselves are not a source of error.

 the ionicity is not important for sapphire in HRTEM image simulations.⁹ This was verified in the present work. It contradicts the findings of Stobbs and Stobbs⁷ where the ionicity in sapphire seems to be important for HRTEM image simulations. The chosen high defocus value of -750 Å in most of the HRTEM image simulations (Figs. 7–10) reflects the maximum difference between the conventional HRTEM image simulation (Doyle and Turner scattering factors⁶) and the corrected HRTEM image simulation using first-principles calculations of the charge density redistribution. *Ab initio* HRTEM image simulations on polar {111} Ag-MgO interfaces reveal significant differences in contrast compared with conventional image simulations.

At oxygen-terminated {111} Ag-MgO the bonding between metal and oxide is responsible for the difference in brightness at the interface comparing conventional and ab initio HRTEM image simulations. In contrast, the magnesium-terminated {111} Ag-MgO interface shows no contrast change between conventional and ab initio HRTEM image simulations. The enhanced contrast compared with the contrast in the bulk structure at the interface originates from the position of the Ag atoms at the interface rather than from bonding changes across the Ag-MgO interface. We include calculations for both the O-terminated and Mg-terminate interfaces. Although it has been shown previously³² that the Mg-terminated interface is less favorable to adhesion than the oxygen-terminated interface, we would not rule out its existence under all conditions, for example if the ratio of Mg to O activities were higher. From an experimental viewpoint is should be realized that both terminations are feasible, depending on the partial pressure of oxygen.^{33,34}

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